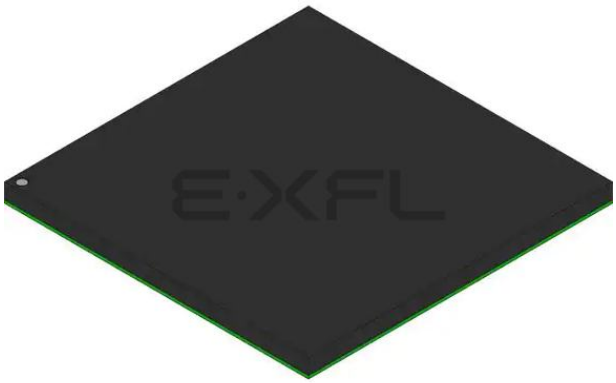

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Details	
Product Status	Active
Number of LABs/CLBs	-
Number of Logic Elements/Cells	-
Total RAM Bits	-
Number of I/O	500
Number of Gates	-
Voltage - Supply	1.15V ~ 1.25V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 85°C (TJ)
Package / Case	672-BBGA, FCBGA
Supplier Device Package	672-FBGA (27x27)
Purchase URL	https://www.e-xfl.com/pro/item?MUrl=&PartUrl=ep2s30f672c4

After compilation, check the information messages for a full list of I/O, DQ, LVDS, and other pins that are not available because of the selected migration path.

Table 1–4 lists the Stratix II device package offerings and shows the total number of non-migratable user I/O pins when migrating from one density device to a larger density device. Additional I/O pins may not be migratable if migrating from the larger device to the smaller density device.

When moving from one density to a larger density, the larger density device may have fewer user I/O pins. The larger device requires more power and ground pins to support the additional logic within the device. Use the Quartus II Pin Planner to determine which user I/O pins are migratable between the two devices.

Table 1–4. Total Number of Non-Migratable I/O Pins for Stratix II Vertical Migration Paths

Vertical Migration Path	484-Pin FineLine BGA	672-Pin FineLine BGA	780-Pin FineLine BGA	1020-Pin FineLine BGA	1508-Pin FineLine BGA
EP2S15 to EP2S30	0 *(1)*	0			
EP2S15 to EP2S60	8 *(1)*	0			
EP2S30 to EP2S60	8 *(1)*	8			
EP2S60 to EP2S90				0	
EP2S60 to EP2S130				0	
EP2S60 to EP2S180				0	
EP2S90 to EP2S130			0 *(1)*	16	17
EP2S90 to EP2S180				16	0
EP2S130 to EP2S180				0	0

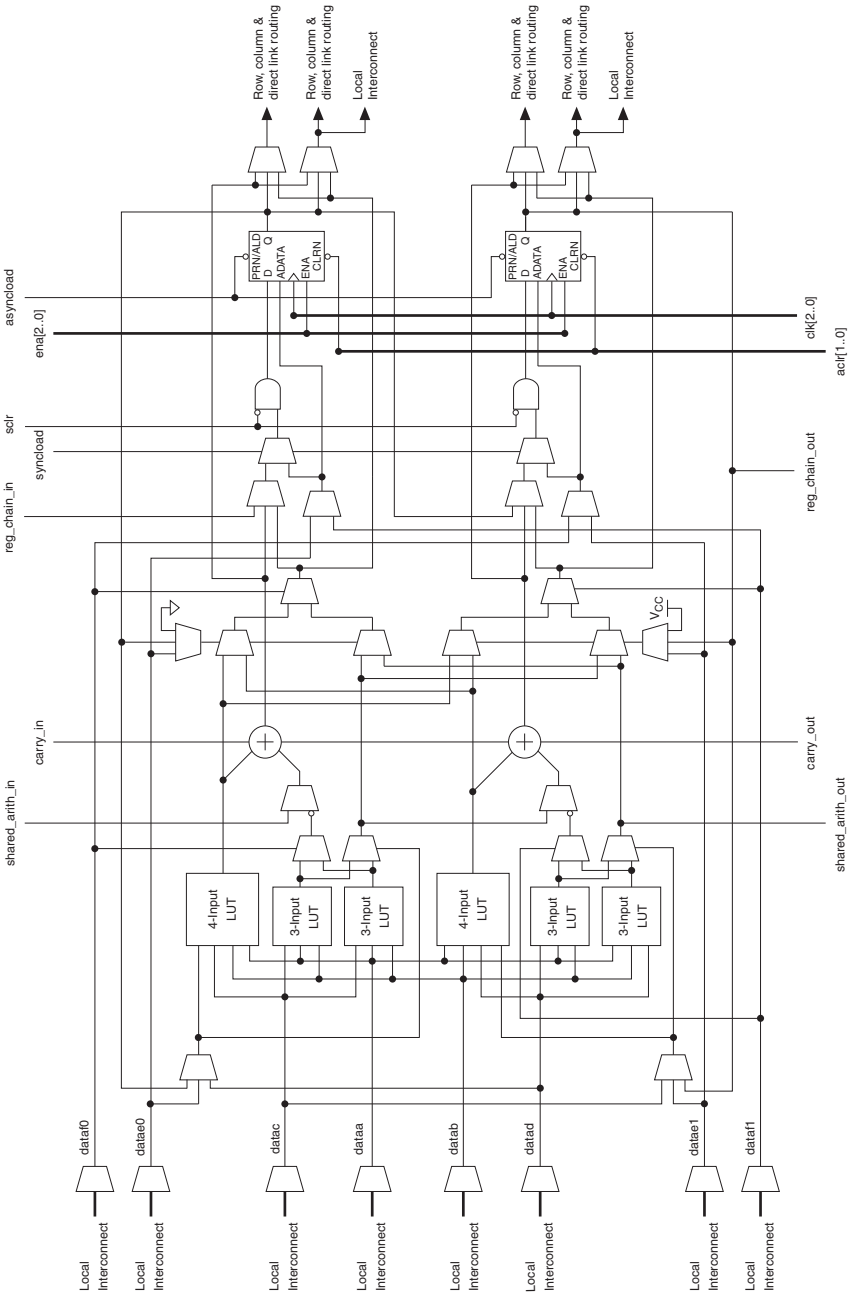
Note to Table 1–4:

(1) Some of the DQ/DQS pins are not migratable. Refer to the Quartus II software information messages for more detailed information.

To determine if your user I/O assignments are correct, run the I/O Assignment Analysis command in the Quartus II software (Processing > Start > Start I/O Assignment Analysis).

Refer to the *I/O Management* chapter in volume 2 of the *Quartus II Handbook* for more information on pin migration.

Figure 2–6. Stratix II ALM Details



One ALM contains two programmable registers. Each register has data, clock, clock enable, synchronous and asynchronous clear, asynchronous load data, and synchronous and asynchronous load/preset inputs. Global signals, general-purpose I/O pins, or any internal logic can drive the register's clock and clear control signals. Either general-purpose I/O pins or internal logic can drive the clock enable, preset, asynchronous load, and asynchronous load data. The asynchronous load data input comes from the `datae` or `dataf` input of the ALM, which are the same inputs that can be used for register packing. For combinational functions, the register is bypassed and the output of the LUT drives directly to the outputs of the ALM.

Each ALM has two sets of outputs that drive the local, row, and column routing resources. The LUT, adder, or register output can drive these output drivers independently (see Figure 2–6). For each set of output drivers, two ALM outputs can drive column, row, or direct link routing connections, and one of these ALM outputs can also drive local interconnect resources. This allows the LUT or adder to drive one output while the register drives another output. This feature, called register packing, improves device utilization because the device can use the register and the combinational logic for unrelated functions. Another special packing mode allows the register output to feed back into the LUT of the same ALM so that the register is packed with its own fan-out LUT. This provides another mechanism for improved fitting. The ALM can also drive out registered and unregistered versions of the LUT or adder output.

See the *Performance & Logic Efficiency Analysis of Stratix II Devices White Paper* for more information on the efficiencies of the Stratix II ALM and comparisons with previous architectures.

ALM Operating Modes

The Stratix II ALM can operate in one of the following modes:

- Normal mode
- Extended LUT mode
- Arithmetic mode
- Shared arithmetic mode

Each mode uses ALM resources differently. In each mode, eleven available inputs to the ALM--the eight data inputs from the LAB local interconnect; `carry-in` from the previous ALM or LAB; the shared arithmetic chain connection from the previous ALM or LAB; and the register chain connection--are directed to different destinations to implement the desired logic function. LAB-wide signals provide clock, asynchronous clear, asynchronous preset/load, synchronous clear,

The Quartus II Compiler automatically creates carry chain logic during design processing, or you can create it manually during design entry. Parameterized functions such as LPM functions automatically take advantage of carry chains for the appropriate functions.

The Quartus II Compiler creates carry chains longer than 16 (8 ALMs in arithmetic or shared arithmetic mode) by linking LABs together automatically. For enhanced fitting, a long carry chain runs vertically allowing fast horizontal connections to TriMatrix memory and DSP blocks. A carry chain can continue as far as a full column.

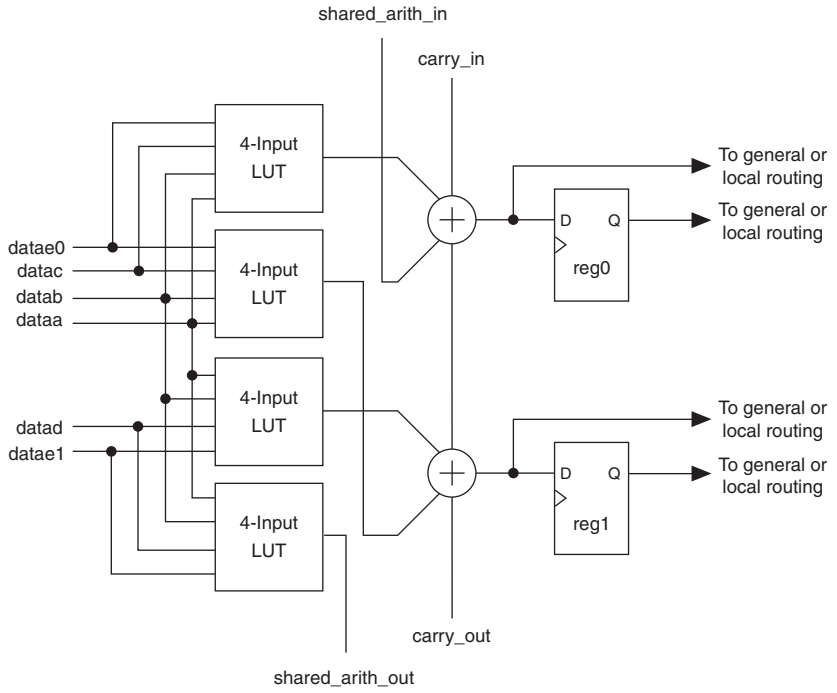
To avoid routing congestion in one small area of the device when a high fan-in arithmetic function is implemented, the LAB can support carry chains that only utilize either the top half or the bottom half of the LAB before connecting to the next LAB. This leaves the other half of the ALMs in the LAB available for implementing narrower fan-in functions in normal mode. Carry chains that use the top four ALMs in the first LAB carry into the top half of the ALMs in the next LAB within the column. Carry chains that use the bottom four ALMs in the first LAB carry into the bottom half of the ALMs in the next LAB within the column. Every other column of LABs is top-half bypassable, while the other LAB columns are bottom-half bypassable.

See the "MultiTrack Interconnect" on page 2–22 section for more information on carry chain interconnect.

Shared Arithmetic Mode

In shared arithmetic mode, the ALM can implement a three-input add. In this mode, the ALM is configured with four 4-input LUTs. Each LUT either computes the sum of three inputs or the carry of three inputs. The output of the carry computation is fed to the next adder (either to `adder1` in the same ALM or to `adder0` of the next ALM in the LAB) via a dedicated connection called the shared arithmetic chain. This shared arithmetic chain can significantly improve the performance of an adder tree by reducing the number of summation stages required to implement an adder tree. Figure 2–13 shows the ALM in shared arithmetic mode.

Figure 2–13. ALM in Shared Arithmetic Mode



Note to Figure 2–13:
(1) Inputs `dataf0` and `dataf1` are available for register packing in shared arithmetic mode.

Adder trees can be found in many different applications. For example, the summation of the partial products in a logic-based multiplier can be implemented in a tree structure. Another example is a correlator function that can use a large adder tree to sum filtered data samples in a given time frame to recover or to de-spread data which was transmitted utilizing spread spectrum technology.

An example of a three-bit add operation utilizing the shared arithmetic mode is shown in Figure 2–14. The partial sum `(S[2..0])` and the partial carry `(C[2..0])` is obtained using the LUTs, while the result `(R[2..0])` is computed using the dedicated adders.

Table 2–5 shows the number of DSP blocks in each Stratix II device.

Table 2–5. DSP Blocks in Stratix II Devices *Note (1)*

Device	DSP Blocks	Total 9 × 9 Multipliers	Total 18 × 18 Multipliers	Total 36 × 36 Multipliers
EP2S15	12	96	48	12
EP2S30	16	128	64	16
EP2S60	36	288	144	36
EP2S90	48	384	192	48
EP2S130	63	504	252	63
EP2S180	96	768	384	96

Note to Table 2–5:

(1) Each device has either the numbers of 9 × 9-, 18 × 18-, or 36 × 36-bit multipliers shown. The total number of multipliers for each device is not the sum of all the multipliers.

DSP block multipliers can optionally feed an adder/subtractor or accumulator in the block depending on the configuration. This makes routing to ALMs easier, saves ALM routing resources, and increases performance, because all connections and blocks are in the DSP block. Additionally, the DSP block input registers can efficiently implement shift registers for FIR filter applications, and DSP blocks support Q1.15 format rounding and saturation.

Figure 2–28 shows the top-level diagram of the DSP block configured for 18 × 18-bit multiplier mode.

Table 2–14. DQS & DQ Bus Mode Support (Part 2 of 2) *Note (1)*

Device	Package	Number of ×4 Groups	Number of ×8/×9 Groups	Number of ×16/×18 Groups	Number of ×32/×36 Groups
EP2S90	484-pin Hybrid FineLine BGA	8	4	0	0
	780-pin FineLine BGA	18	8	4	0
	1,020-pin FineLine BGA	36	18	8	4
	1,508-pin FineLine BGA	36	18	8	4
EP2S130	780-pin FineLine BGA	18	8	4	0
	1,020-pin FineLine BGA	36	18	8	4
	1,508-pin FineLine BGA	36	18	8	4
EP2S180	1,020-pin FineLine BGA	36	18	8	4
	1,508-pin FineLine BGA	36	18	8	4

Notes to Table 2–14:
(1) Check the pin table for each DQS/DQ group in the different modes.

A compensated delay element on each DQS pin automatically aligns input DQS synchronization signals with the data window of their corresponding DQ data signals. The DQS signals drive a local DQS bus in the top and bottom I/O banks. This DQS bus is an additional resource to the I/O clocks and is used to clock DQ input registers with the DQS signal.

The Stratix II device has two phase-shifting reference circuits, one on the top and one on the bottom of the device. The circuit on the top controls the compensated delay elements for all DQS pins on the top. The circuit on the bottom controls the compensated delay elements for all DQS pins on the bottom.

Each phase-shifting reference circuit is driven by a system reference clock, which must have the same frequency as the DQS signal. Clock pins `CLK[15..12]p` feed the phase circuitry on the top of the device and clock pins `CLK[7..4]p` feed the phase circuitry on the bottom of the device. In addition, PLL clock outputs can also feed the phase-shifting reference circuits.

Figure 2–56 illustrates the phase-shift reference circuit control of each DQS delay shift on the top of the device. This same circuit is duplicated on the bottom of the device.

Table 2–16. Stratix II Supported I/O Standards (Part 2 of 2)

I/O Standard	Type	Input Reference Voltage (V_{REF}) (V)	Output Supply Voltage (V_{CCIO}) (V)	Board Termination Voltage (V_{TT}) (V)
SSTL-2 Class I and II	Voltage-referenced	1.25	2.5	1.25

Notes to Table 2–16:

(1) This I/O standard is only available on input and output column clock pins.

(2) This I/O standard is only available on input clock pins and DQS pins in I/O banks 3, 4, 7, and 8, and output clock pins in I/O banks 9,10, 11, and 12.

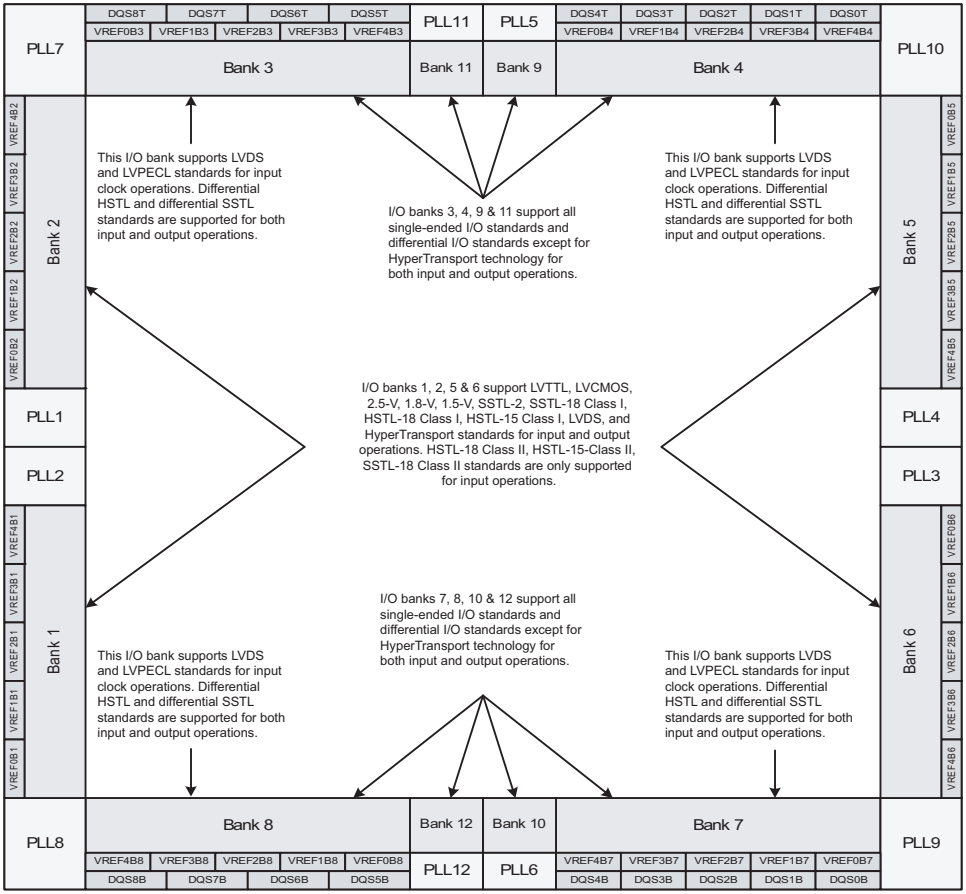
(3) V_{CCIO} is 3.3 V when using this I/O standard in input and output column clock pins (in I/O banks 9, 10, 11, and 12). The clock input pins supporting LVDS on banks 3, 4, 7, and 8 use V_{CCINT} for LVDS input operations and have no dependency on the V_{CCIO} level of the bank.

(4) 1.2-V HSTL is only supported in I/O banks 4,7, and 8.

For more information on I/O standards supported by Stratix II I/O banks, refer to the *Selectable I/O Standards in Stratix II & Stratix II GX Devices* chapter in volume 2 of the *Stratix II Device Handbook* or the *Stratix II GX Device Handbook*.

Stratix II devices contain eight I/O banks and four enhanced PLL external clock output banks, as shown in Figure 2–57. The four I/O banks on the right and left of the device contain circuitry to support high-speed differential I/O for LVDS and HyperTransport inputs and outputs. These banks support all Stratix II I/O standards except PCI or PCI-X I/O pins, and SSTL-18 Class II and HSTL outputs. The top and bottom I/O banks support all single-ended I/O standards. Additionally, enhanced PLL external clock output banks allow clock output capabilities such as differential support for SSTL and HSTL.

Figure 2–57. Stratix II I/O Banks *Notes (1), (2), (3), (4)*



Notes to Figure 2–57:

(1) Figure 2–57 is a top view of the silicon die that corresponds to a reverse view for flip-chip packages. It is a graphical representation only.

(2) Depending on the size of the device, different device members have different numbers of V_{REF} groups. Refer to the pin list and the Quartus II software for exact locations.

(3) Banks 9 through 12 are enhanced PLL external clock output banks. These PLL banks utilize the adjacent V_{REF} group when voltage-referenced standards are implemented. For example, if an SSTL input is implemented in PLL bank 10, the voltage level at VREFB7 is the reference voltage level for the SSTL input.

(4) Horizontal I/O banks feature SERDES and DPA circuitry for high speed differential I/O standards. See the *High Speed Differential I/O Interfaces in Stratix II & Stratix II GX Devices* chapter of the *Stratix II Device Handbook, Volume 2* or the *Stratix II GX Device Handbook, Volume 2* for more information on differential I/O standards.

Table 2–23. EP2S60 Differential Channels *Note (1)*

Package	Transmitter/ Receiver	Total Channels	Center Fast PLLs				Corner Fast PLLs *(4)*			
			PLL 1	PLL 2	PLL 3	PLL 4	PLL 7	PLL 8	PLL 9	PLL 10
484-pin FineLine BGA	Transmitter	38 *(2)*	10	9	9	10	10	9	9	10
		(3)	19	19	19	19	-	-	-	-
	Receiver	42 *(2)*	11	10	10	11	11	10	10	11
		(3)	21	21	21	21	-	-	-	-
672-pin FineLine BGA	Transmitter	58 *(2)*	16	13	13	16	16	13	13	16
		(3)	29	29	29	29	-	-	-	-
	Receiver	62 *(2)*	17	14	14	17	17	14	14	17
		(3)	31	31	31	31	-	-	-	-
1,020-pin FineLine BGA	Transmitter	84 *(2)*	21	21	21	21	21	21	21	21
		(3)	42	42	42	42	-	-	-	-
	Receiver	84 *(2)*	21	21	21	21	21	21	21	21
		(3)	42	42	42	42	-	-	-	-

Table 2–24. EP2S90 Differential Channels *Note (1)*

Package	Transmitter/ Receiver	Total Channels	Center Fast PLLs				Corner Fast PLLs *(4)*			
			PLL 1	PLL 2	PLL 3	PLL 4	PLL 7	PLL 8	PLL 9	PLL 10
484-pin Hybrid FineLine BGA	Transmitter	38 *(2)*	10	9	9	10	-	-	-	-
		(3)	19	19	19	19	-	-	-	-
	Receiver	42 *(2)*	11	10	10	11	-	-	-	-
		(3)	21	21	21	21	-	-	-	-
780-pin FineLine BGA	Transmitter	64 *(2)*	16	16	16	16	-	-	-	
		(3)	32	32	32	32	-	-	-	-
	Receiver	68 *(2)*	17	17	17	17	-	-	-	-
		(3)	34	34	34	34	-	-	-	
1,020-pin FineLine BGA	Transmitter	90 *(2)*	23	22	22	23	23	22	22	23
		(3)	45	45	45	45	-	-	-	-
	Receiver	94 *(2)*	23	24	24	23	23	24	24	23
		(3)	46	46	46	46	-	-	-	-
1,508-pin FineLine BGA	Transmitter	118 *(2)*	30	29	29	30	30	29	29	30
		(3)	59	59	59	59	-	-	-	-
	Receiver	118 *(2)*	30	29	29	30	30	29	29	30
		(3)	59	59	59	59	-	-	-	-

The PLL_ENA pin and the configuration input pins (Table 3–4) have a dual buffer design: a 3.3-V/2.5-V input buffer and a 1.8-V/1.5-V input buffer. The VCCSEL input pin selects which input buffer is used. The 3.3-V/2.5-V input buffer is powered by $V_{CCPD,}$ while the 1.8-V/1.5-V input buffer is powered by V_{CCIO}. Table 3–4 shows the pins affected by VCCSEL.

Table 3–4. Pins Affected by the Voltage Level at VCCSEL

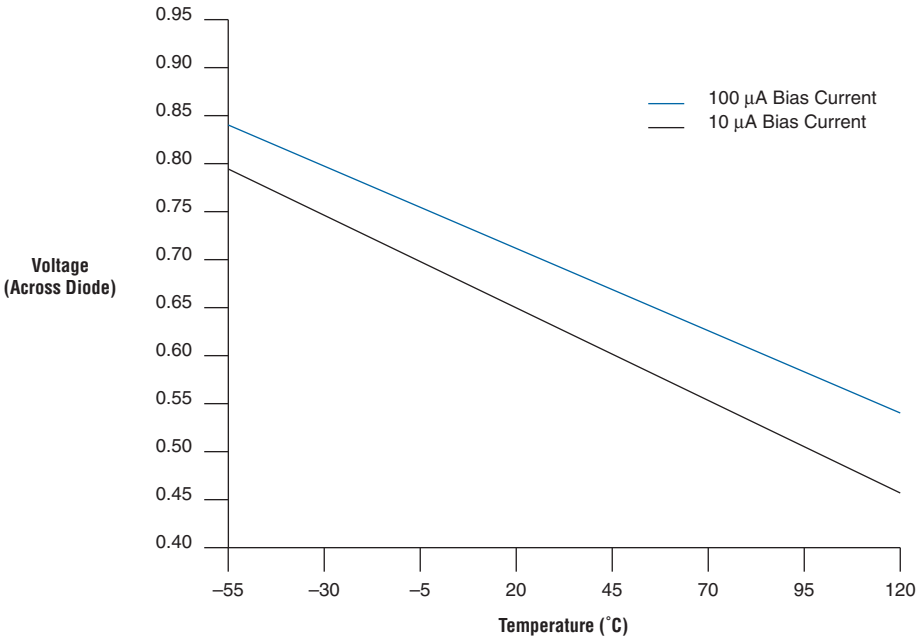
Pin	VCCSEL = LOW (connected to GND)	VCCSEL = HIGH (connected to V_{CCPD})
nSTATUS (when used as an input)	3.3/2.5-V input buffer is selected. Input buffer is powered by V_{CCPD}.	1.8/1.5-V input buffer is selected. Input buffer is powered by V_{CCIO} of the I/O bank.
nCONFIG		
CONF_DONE (when used as an input)		
DATA[7..0]		
nCE		
DCLK (when used as an input)		
CS		
nWS		
nRS		
nCS		
CLKUSR		
DEV_OE		
DEV_CLRn		
RUnLU		
PLL_ENA		

VCCSEL is sampled during power-up. Therefore, the VCCSEL setting cannot change on the fly or during a reconfiguration. The VCCSEL input buffer is powered by V_{CCINT} and must be hardwired to V_{CCPD} or ground. A logic high VCCSEL connection selects the 1.8-V/1.5-V input buffer, and a logic low selects the 3.3-V/2.5-V input buffer. VCCSEL should be set to comply with the logic levels driven out of the configuration device or MAX® II/microprocessor.

If you need to support configuration input voltages of 3.3 V/2.5 V, you should set the VCCSEL to a logic low; you can set the V_{CCIO} of the I/O bank that contains the configuration inputs to any supported voltage. If

The temperature-sensing diode works for the entire operating range, as shown in Figure 3–2.

Figure 3–2. Temperature vs. Temperature-Sensing Diode Voltage



The temperature sensing diode is a very sensitive circuit which can be influenced by noise coupled from other traces on the board, and possibly within the device package itself, depending on device usage. The interfacing device registers temperature based on milivolts of difference as seen at the TSD. Switching I/O near the TSD pins can affect the temperature reading. Altera recommends you take temperature readings during periods of no activity in the device (for example, standby mode where no clocks are toggling in the device), such as when the nearby I/Os are at a DC state, and disable clock networks in the device.

Automated Single Event Upset (SEU) Detection

Stratix II devices offer on-chip circuitry for automated checking of single event upset (SEU) detection. Some applications that require the device to operate error free at high elevations or in close proximity to Earth's North or South Pole require periodic checks to ensure continued data integrity. The error detection cyclic redundancy check (CRC) feature controlled by

Document Revision History

Table 4–1 shows the revision history for this chapter.

Table 4–1. Document Revision History

Date and Document Version	Changes Made	Summary of Changes
May 2007, v3.2	Moved the Document Revision History section to the end of the chapter.	—
April 2006, v3.1	• Updated "Signal Pins Do Not Drive the VCCIO, VCCINT or VCCPD Power Supplies" section.	• Updated hot socketing AC specification.
May 2005, v3.0	• Updated "Signal Pins Do Not Drive the VCCIO, VCCINT or VCCPD Power Supplies" section. • Removed information on ESD protection.	—
January 2005, v2.1	Updated input rise and fall time.	—
January 2005, v2.0	Updated the "Hot Socketing Feature Implementation in Stratix II Devices", "ESD Protection", and "Power-On Reset Circuitry" sections.	—
July 2004, v1.1	• Updated all tables. • Added tables.	—
February 2004, v1.0	Added document to the Stratix II Device Handbook.	—

Table 5–36. Stratix II Performance Notes (Part 6 of 6) Note (1)

Applications		Resources Used			Performance				
		ALUTs	TriMatrix Memory Blocks	DSP Blocks	-3 Speed Grade (2)	-3 Speed Grade (3)	-4 Speed Grade	-5 Speed Grade	Unit
Larger designs	8-bit, 1024-point, quadrant output, four parallel FFT engines, buffered burst, three multipliers five adders FFT function	7385	60	36	359.58	352.98	312.01	278.00	MHz
	8-bit, 1024-point, quadrant output, four parallel FFT engines, buffered burst, four multipliers and two adders FFT function	6601	60	48	371.88	355.74	327.86	277.62	MHz

Notes for Table 5–36:

(1) These design performance numbers were obtained using the Quartus II software version 5.0 SP1.
(2) These numbers apply to -3 speed grade EP2S15, EP2S30, EP2S60, and EP2S90 devices.
(3) These numbers apply to -3 speed grade EP2S130 and EP2S180 devices.
(4) This application uses registered inputs and outputs.
(5) This application uses registered multiplier input and output stages within the DSP block.
(6) This application uses registered multiplier input, pipeline, and output stages within the DSP block.
(7) This application uses registered multiplier input with output of the multiplier stage feeding the accumulator or subtractor within the DSP block.
(8) This application uses the same clock source that is globally routed and connected to ports A and B.
(9) This application uses locally routed clocks or differently sourced clocks for ports A and B.

Table 5–47. EP2S15 Row Pins Global Clock Timing Parameters

Parameter	Minimum Timing		-3 Speed Grade	-4 Speed Grade	-5 Speed Grade	Unit
	Industrial	Commercial				
t_{CIN}	1.206	1.262	2.113	2.422	2.815	ns
t_{COUT}	1.211	1.267	2.109	2.418	2.810	ns
t_{PLLCIN}	-0.125	-0.138	-0.023	-0.038	-0.056	ns
$t_{PLLCOUT}$	-0.12	-0.133	-0.027	-0.042	-0.061	ns

EP2S30 Clock Timing Parameters

Tables 5–48 through 5–51 show the maximum clock timing parameters for EP2S30 devices.

Table 5–48. EP2S30 Column Pins Regional Clock Timing Parameters

Parameter	Minimum Timing		-3 Speed Grade	-4 Speed Grade	-5 Speed Grade	Unit
	Industrial	Commercial				
t_{CIN}	1.553	1.627	2.639	3.025	3.509	ns
t_{COUT}	1.396	1.462	2.397	2.747	3.185	ns
t_{PLLCIN}	0.114	0.113	0.225	0.248	0.28	ns
$t_{PLLCOUT}$	-0.043	-0.052	-0.017	-0.03	-0.044	ns

Table 5–49. EP2S30 Column Pins Global Clock Timing Parameters

Parameter	Minimum Timing		-3 Speed Grade	-4 Speed Grade	-5 Speed Grade	Unit
	Industrial	Commercial				
t_{CIN}	1.539	1.613	2.622	3.008	3.501	ns
t_{COUT}	1.382	1.448	2.380	2.730	3.177	ns
t_{PLLCIN}	0.101	0.098	0.209	0.229	0.267	ns
$t_{PLLCOUT}$	-0.056	-0.067	-0.033	-0.049	-0.057	ns

Table 5–79. Maximum Output Clock Toggle Rate Derating Factors (Part 4 of 5)

I/O Standard	Drive Strength	Maximum Output Clock Toggle Rate Derating Factors (ps/pF)								
		Column I/O Pins			Row I/O Pins			Dedicated Clock Outputs		
		-3	-4	-5	-3	-4	-5	-3	-4	-5
Differential SSTL-18 Class I *(3)*	4 mA	458	570	570	-	-	-	505	570	570
	6 mA	305	380	380	-	-	-	336	380	380
	8 mA	225	282	282	-	-	-	248	282	282
	10 mA	167	220	220	-	-	-	190	220	220
	12 mA	129	175	175	-	-	-	148	175	175
Differential SSTL-18 Class II *(3)*	8 mA	173	206	206	-	-	-	155	206	206
	16 mA	150	160	160	-	-	-	140	160	160
	18 mA	120	130	130	-	-	-	110	130	130
	20 mA	109	127	127	-	-	-	94	127	127
1.8-V Differential HSTL Class I *(3)*	4 mA	245	282	282	-	-	-	229	282	282
	6 mA	164	188	188	-	-	-	153	188	188
	8 mA	123	140	140	-	-	-	114	140	140
	10 mA	110	124	124	-	-	-	108	124	124
	12 mA	97	110	110	-	-	-	104	110	110
1.8-V Differential HSTL Class II *(3)*	16 mA	101	104	104	-	-	-	99	104	104
	18 mA	98	102	102	-	-	-	93	102	102
	20 mA	93	99	99	-	-	-	88	99	99
1.5-V Differential HSTL Class I *(3)*	4 mA	168	196	196	-	-	-	188	196	196
	6 mA	112	131	131	-	-	-	125	131	131
	8 mA	84	99	99	-	-	-	95	99	99
	10 mA	87	98	98	-	-	-	90	98	98
	12 mA	86	98	98	-	-	-	87	98	98
1.5-V Differential HSTL Class II *(3)*	16 mA	95	101	101	-	-	-	96	101	101
	18 mA	95	100	100	-	-	-	101	100	100
	20 mA	94	101	101	-	-	-	104	101	101
3.3-V PCI		134	177	177	-	-	-	143	177	177
3.3-V PCI-X		134	177	177	-	-	-	143	177	177
LVDS		-	-	-	155 *(1)*	155 *(1)*	155 *(1)*	134	134	134
HyperTransport technology		-	-	-	155 *(1)*	155 *(1)*	155 *(1)*	-	-	-
LVPECL *(4)*		-	-	-	-	-	-	134	134	134

Table 5–89. High-Speed I/O Specifications for -3 Speed Grade (Part 2 of 2) *Notes (1), (2)*

Symbol	Conditions			-3 Speed Grade			Unit
				Min	Typ	Max	
f_{HSDR} (data rate)	J = 4 to 10 (LVDS, HyperTransport technology)			150		1,040	Mbps
	J = 2 (LVDS, HyperTransport technology)			*(4)*		760	Mbps
	J = 1 (LVDS only)			*(4)*		500	Mbps
$f_{HSDRDPA}$ (DPA data rate)	J = 4 to 10 (LVDS, HyperTransport technology)			150		1,040	Mbps
TCCS	All differential standards			-		200	ps
SW	All differential standards			330		-	ps
Output jitter						190	ps
Output t_{RISE}	All differential I/O standards					160	ps
Output t_{FALL}	All differential I/O standards					180	ps
t_{DUTY}				45	50	55	%
DPA run length						6,400	UI
DPA jitter tolerance	Data channel peak-to-peak jitter			0.44			UI
DPA lock time	**Standard**	**Training Pattern**	**Transition Density**				Number of repetitions
	SPI-4	0000000000 1111111111	10%	256			
	Parallel Rapid I/O	00001111	25%	256			
		10010000	50%	256			
	Miscellaneous	10101010	100%	256			
		01010101		256			

Notes to Table 5–89:

(1) When J = 4 to 10, the SERDES block is used.

(2) When J = 1 or 2, the SERDES block is bypassed.

(3) The input clock frequency and the W factor must satisfy the following fast PLL VCO specification: 150 ≤ input clock frequency × W ≤ 1,040.

(4) The minimum specification is dependent on the clock source (fast PLL, enhanced PLL, clock pin, and so on) and the clock routing resource (global, regional, or local) utilized. The I/O differential buffer and input register do not have a minimum toggle rate.

Table 5–93. Fast PLL Specifications

Name	Description	Min	Typ	Max	Unit
f_{IN}	Input clock frequency (for -3 and -4 speed grade devices)	16.08		717	MHz
	Input clock frequency (for -5 speed grade devices)	16.08		640	MHz
f_{INPFD}	Input frequency to the PFD	16.08		500	MHz
f_{INDUTY}	Input clock duty cycle	40		60	%
$t_{INJITTER}$	Input clock jitter tolerance in terms of period jitter. Bandwidth ≤ 2 MHz		0.5		ns (p-p)
	Input clock jitter tolerance in terms of period jitter. Bandwidth > 2 MHz		1.0		ns (p-p)
f_{VCO}	Upper VCO frequency range for –3 and –4 speed grades	300		1,040	MHz
	Upper VCO frequency range for –5 speed grades	300		840	MHz
	Lower VCO frequency range for –3 and –4 speed grades	150		520	MHz
	Lower VCO frequency range for –5 speed grades	150		420	MHz
f_{OUT}	PLL output frequency to GCLK or RCLK	4.6875		550	MHz
	PLL output frequency to LVDS or DPA clock	150		1,040	MHz
f_{OUT_IO}	PLL clock output frequency to regular I/O pin	4.6875		*(1)*	MHz
$f_{SCANCLK}$	Scanclk frequency			100	MHz
$t_{CONFIGPLL}$	Time required to reconfigure scan chains for fast PLLs		$75/f_{SCANCLK}$		ns
f_{CLBW}	PLL closed-loop bandwidth	1.16	5.00	28.00	MHz
t_{LOCK}	Time required for the PLL to lock from the time it is enabled or the end of the device configuration		0.03	1.00	ms
t_{PLL_PSERR}	Accuracy of PLL phase shift			±15	ps
t_{ARESET}	Minimum pulse width on areset signal.	10			ns
$t_{ARESET\_RECONFIG}$	Minimum pulse width on the areset signal when using PLL reconfiguration. Reset the PLL after scandone goes high.	500			ns

Note to Table 5–93:
(1) Limited by I/O f_{MAX}. See Table 5–77 on page 5–67 for the maximum.

Table 5–103. Document Revision History (Part 2 of 3)

Date and Document Version	Changes Made	Summary of Changes
August, 2006, v4.2	Updated Table 5–73, Table 5–75, Table 5–77, Table 5–78, Table 5–79, Table 5–81, Table 5–85, and Table 5–87.	—
April 2006, v4.1	• Updated Table 5–3. • Updated Table 5–11. • Updated Figures 5–8 and 5–9. • Added parallel on-chip termination information to "On-Chip Termination Specifications" section. • Updated Tables 5–28, 5–30,5–31, and 5–34. • Updated Table 5–78, Tables 5–81 through 5–90, and Tables 5–92, 5–93, and 5–98. • Updated "PLL Timing Specifications" section. • Updated "External Memory Interface Specifications" section. • Added Tables 5–95 and 5–101. • Updated "JTAG Timing Specifications" section, including Figure 5–10 and Table 5–102.	• Changed 0.2 MHz to 2 MHz in Table 5–93. • Added new spec for half period jitter (Table 5–101). • Added support for PLL clock switchover for industrial temperature range. • Changed f_{INPFD} (min) spec from 4 MHz to 2 MHz in Table 5–92. • Fixed typo in $t_{OUTJITTER}$ specification in Table 5–92. • Updated V_{DIF} AC & DC max specifications in Table 5–28. • Updated minimum values for t_{JCH}, t_{JCL}, and t_{JPSU} in Table 5–102. • Update maximum values for t_{JPCO}, t_{JPZX}, and t_{JPXZ} in Table 5–102.
December 2005, v4.0	• Updated "External Memory Interface Specifications" section. • Updated timing numbers throughout chapter.	—
July 2005, v3.1	• Updated HyperTransport technology information in Table 5–13. • Updated "Timing Model" section. • Updated "PLL Timing Specifications" section. • Updated "External Memory Interface Specifications" section.	—
May 2005, v3.0	• Updated tables throughout chapter. • Updated "Power Consumption" section. • Added various tables. • Replaced "Maximum Input & Output Clock Rate" section with "Maximum Input & Output Clock Toggle Rate" section. • Added "Duty Cycle Distortion" section. • Added "External Memory Interface Specifications" section.	—
March 2005, v2.2	Updated tables in "Internal Timing Parameters" section.	—
January 2005, v2.1	Updated input rise and fall time.	—